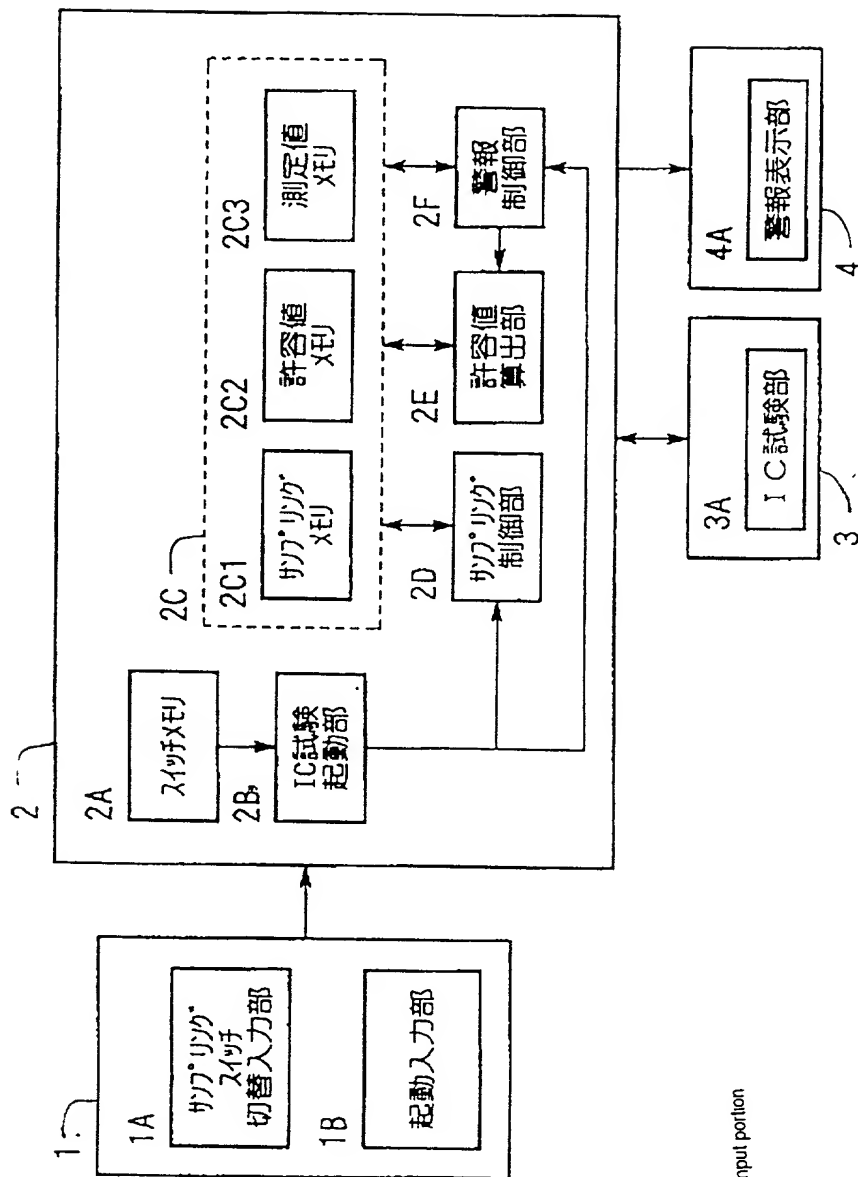


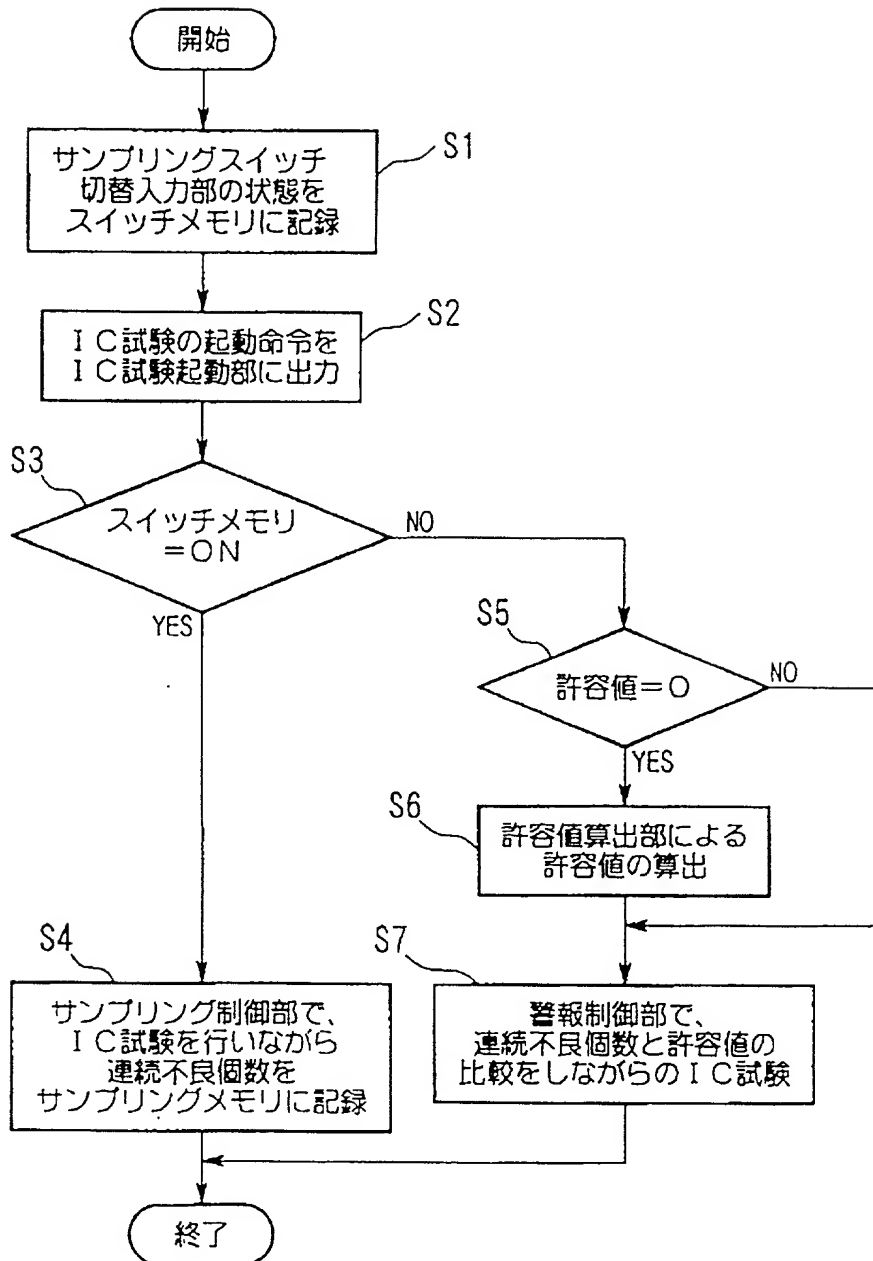
Fig. 1



sampling switch change-over input portion  
 start input portion  
 switch memory  
 IC test start portion  
 memory portion  
 sampling memory  
 permissible value memory  
 measured value memory  
 sampling control portion  
 permissible value calculation portion  
 alarm control portion  
 IC test portion  
 alarm display portion

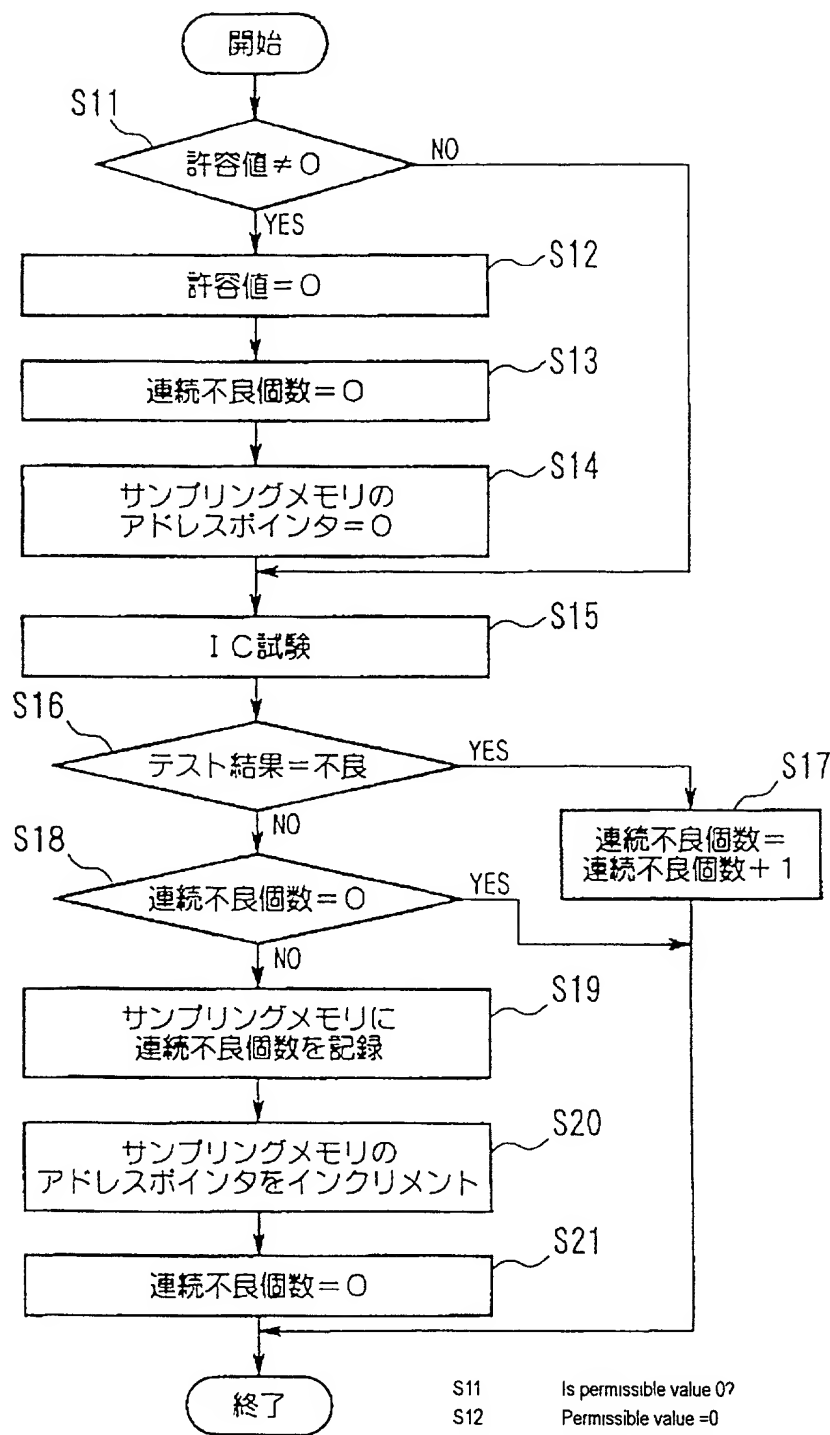
1A  
 1B  
 2A  
 2B  
 2C  
 2C1  
 2C2  
 2C3  
 2D  
 2E  
 2F  
 3A  
 4A

Fig. 2



- S1      Record the state of the sampling switch change-over input portion in switch memory
- S2      Supply start instruction of IC test to IC test start portion
- S3      Is switch memory in ON state?
- S4      Record number of continuous failures in sampling memory in sampling control portion while carrying out IC test.
- S5      Is permissible value 0?
- S6      Calculate permissible value in permissible value calculation portion
- S7      Carry out IC test while comparing number of continuous failures with permissible value in alarm control portion

Fig. 3



- |     |   |
|-----|---|
| S11 | Is permissible value 0?   |
| S12 | Permissible value = 0   |
| S13 | Number of continuous failures = 0                                 |
| S14 | Address pointer of sampling memory = 0                            |
| S15 | IC Test   |
| S16 | Is test result failure?   |
| S17 | Number of continuous failures = number of continuous failures + 1 |
| S18 | Is number of continuous failures 0?                               |
| S19 | Record number of continuous failures into sampling memory         |
| S20 | Increment address pointer of sampling memory                      |
| S21 | Number of continuous failures = 0                                 |

Fig. 4

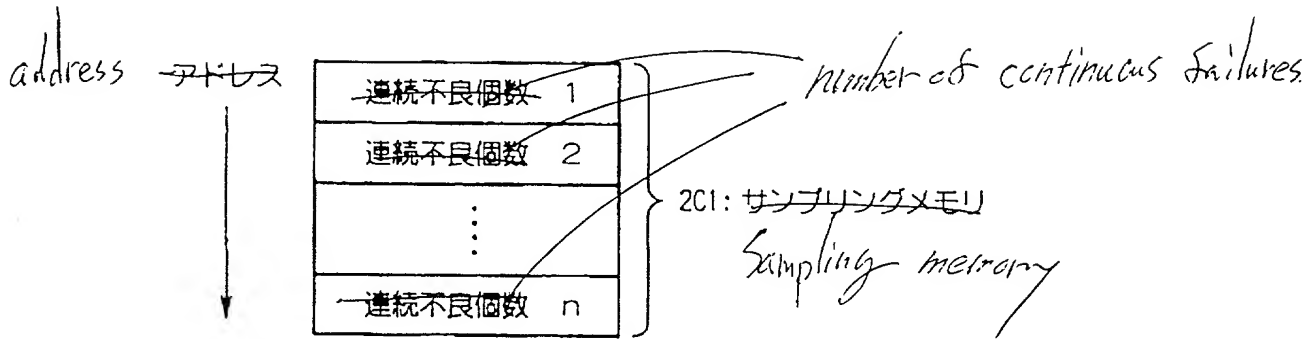
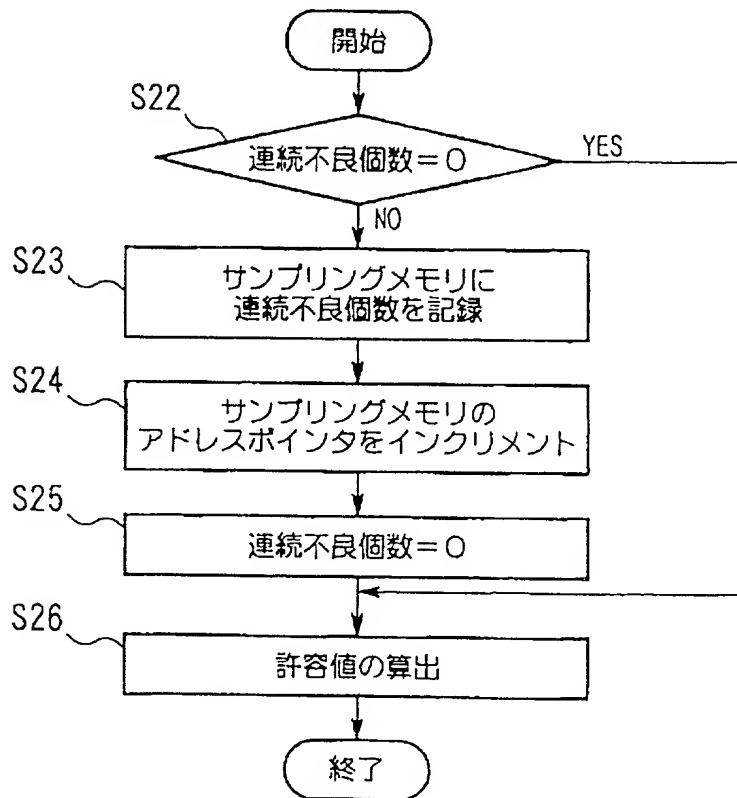
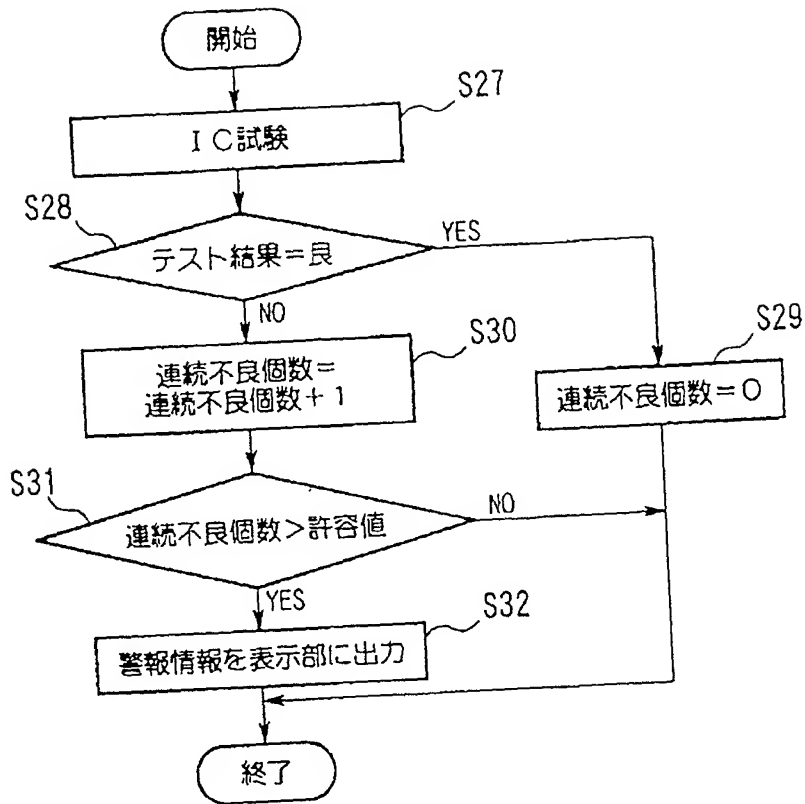


Fig. 5



- S22 Is number of continuous failures 0?
- S23 Record number of continuous failures into sampling memory.
- S24 Increment address pointer of sampling memory
- S25 Number of continuous failures =0
- S26 Calculate permissible value

Fig. 6



- |     |   |
|-----|---|
| S27 | IC Test   |
| S28 | Is test result good?  |
| S29 | Number of continuous failures = 0                                 |
| S30 | Number of continuous failures = number of continuous failures + 1 |
| S31 | Is number of continuous failures larger than permissible value?   |
| S32 | Supply alarm information to display portion                       |

Fig. 7

